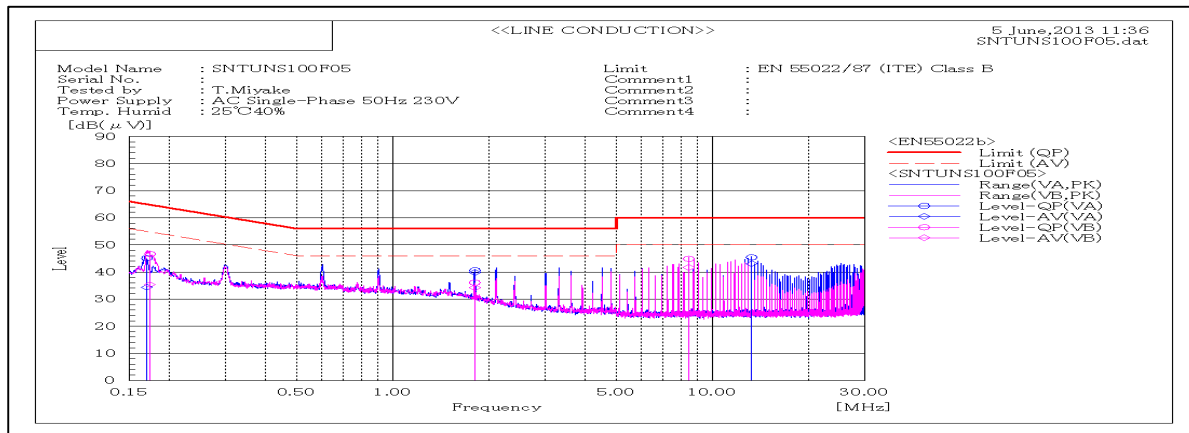
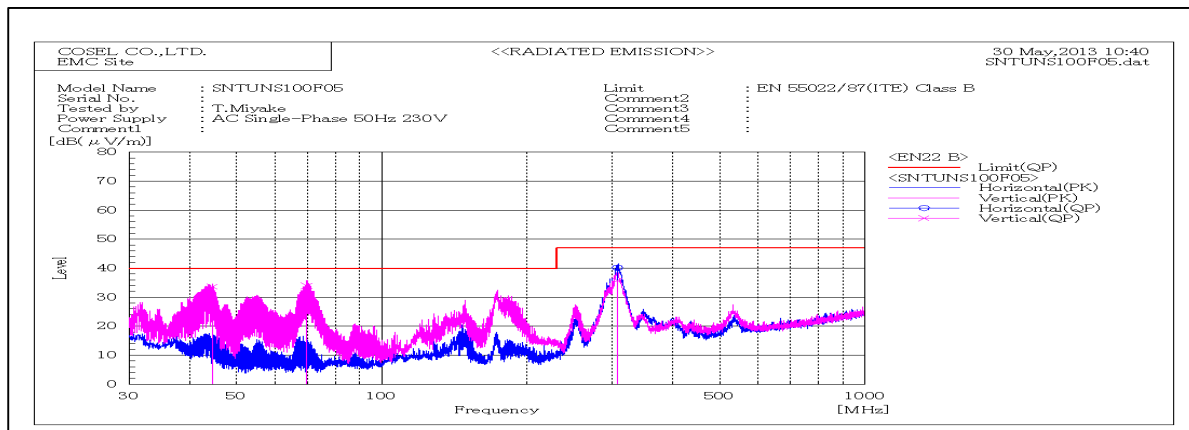


DATA SHEET		Date	19-Jul-13
Model	SNTUNS100F05	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Miyake



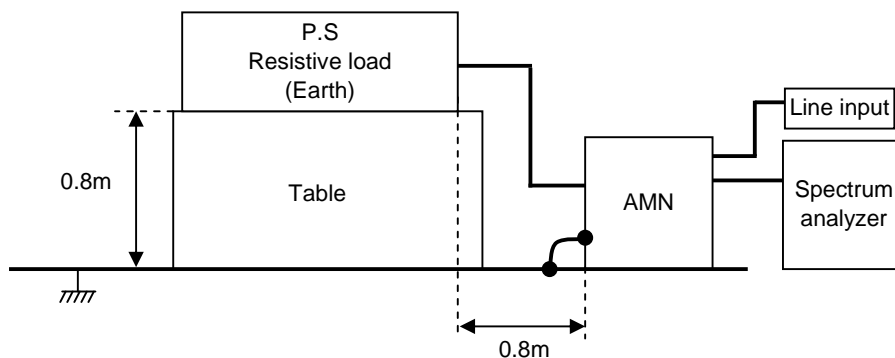
Frequency MHz	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
		QP	AV		QP	AV	QP	AV	QP	AV		
0.1704	VA	24.9	14.2	20.2	45.1	34.4	64.9	54.9	19.8	20.5	Pass	
0.17396	VB	26.4	15.2	20.2	46.6	35.4	64.8	54.8	18.2	19.4	Pass	
1.80694	VB	16	14.1	20.1	36.1	34.2	56	46	19.9	11.8	Pass	
1.80784	VA	20.5	19.7	20.1	40.6	39.8	56	46	15.4	6.2	Pass	
8.43729	VB	24.4	21.2	20.4	44.8	41.6	60	50	15.2	8.4	Pass	
13.2528	VA	24.7	24.7	20.7	45.4	43.1	60	50	14.6	6.9	Pass	



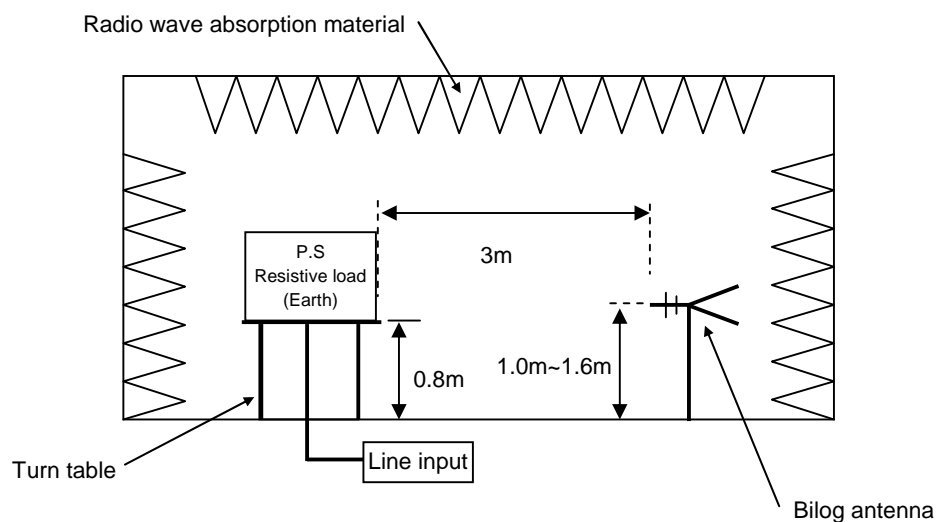
Frequency MHz	Polarization	Stability	Reading dB(μV)		Space Loss dB	Level dB(mW)		Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	AV					
44.517	V	Stable	52.5	-18.9	33.6	40	6.4	Pass	108	167		
69.788	V	Stable	54.5	-20.6	33.9	40	6.1	Pass	118	0		
306.825	V	Stable	52.8	-17.1	35.7	47	11.3	Pass	101	102		
307.074	H	Stable	57.7	-17.5	40.2	47	6.8	Pass	110	258		

DATA SHEET		Date	19-Jul-13
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Miyake

1. Line conduction



2. Radiated emission

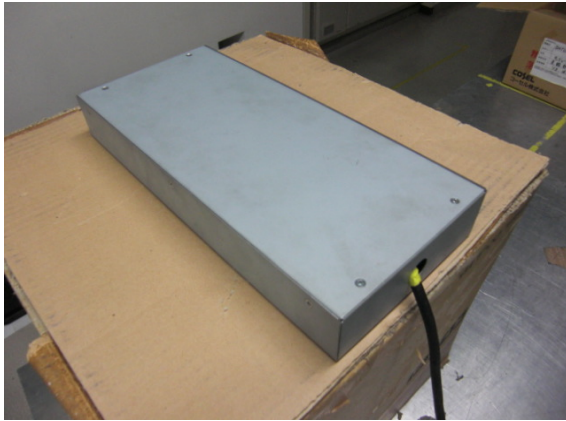


Test:EMI

Model Name: SNTUNS100F Series

○ Photographs of Test Set-Up

LINE CONDUCTION

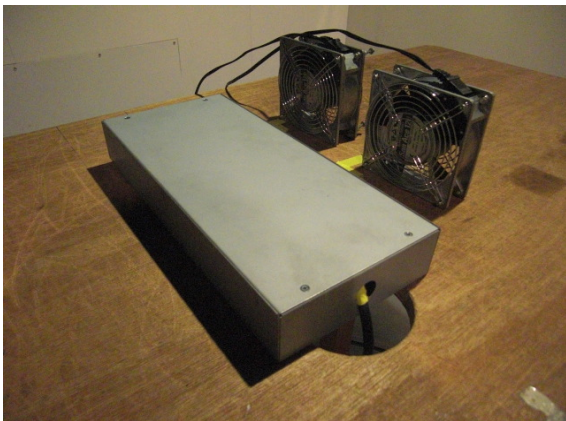


(A) Outside of a case

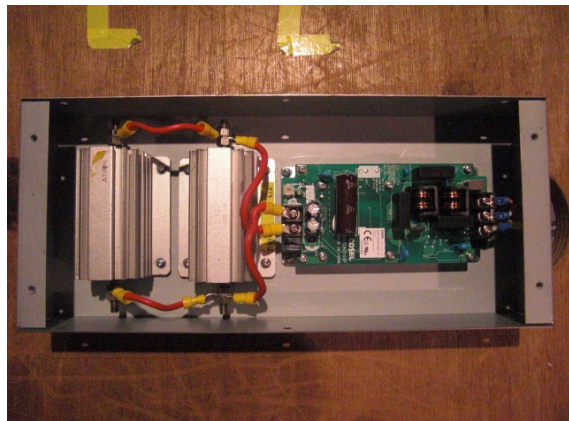


(B) Inside of a case

RADIATED EMISSION



(C) Outside of a case



(D) Inside of a case